

**Search Notes**

Application/Control No.

10/830,049

Examiner

John B. Nguyen

Applicant(s)/Patent under  
Reexamination

OHNISHI ET AL.

Art Unit

2819

**SEARCHED**

Class	Subclass	Date	Examiner
330	285,129	8/20/2005	JN
	279,136		
	134,297		
330	127,140	8/20/2005	JN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
see text search	8/20/2005	JN